

Search Notes

Application/Control No.

10/045,036

Examiner

Tim Phan

Applicant(s)/Patent under
Reexamination

TANAKA ET AL.

Art Unit

3729

29/832

SEARCHED

Class	Subclass	Date	Examiner
29	832	9/22/2003	TP
/	846	/	/
/	847	/	/
430	5	/	/
/	319	/	/
/	321	/	/
Updated	Search	12/8/2005	TP
All	Aboce	/	/
977	DIG.1	/	/

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
29	832	12/8/2005	TP
/	846	/	/
/	847	/	/
nano\$ with pigment with (photomask\$3 or mask\$3 or resist\$3..		/	/

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST Search Attached	12/8/2005	TP